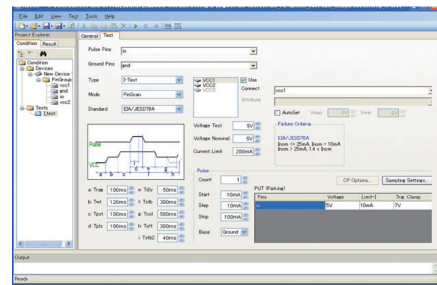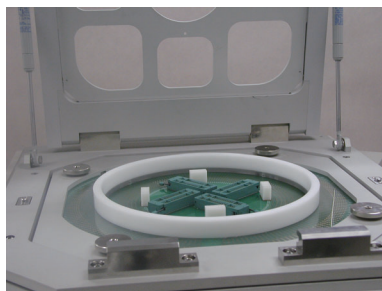## Latch-up test and measurement result

Setting of Latch-up test

The setting for the timing of inserting pulse or the time width with confirming the visual figure is possible.

Socket Board and Zap unit

Socket board
Max. 8 sockets can be installed, and simultaneous zapping to each socket (these needs to discuss) is possible.
Simultaneous zapping makes test time shorter.
Making of socket board that adaptable to every package is possible.
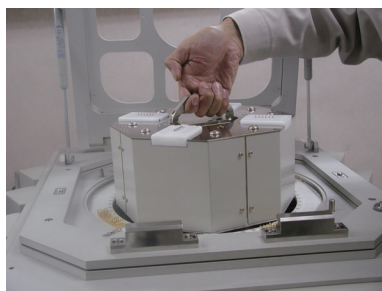
Zap unit
Zap unit can be put and removed easily with desorption method.
Machine Model (MM)×2 and Human Body Model (HBM)×2 are featured as standard. Making zap unit as your option request is possible.

This device uses mercury relays.
If you have any questions, please contact us.

Full Automatic ESD Tester

HED-N5000 series

- Pin expansion to 1024
- Conforms to ESDA_JEDEC JS-001(AEC), JEITA standards

■ Agency

HCA_E_HED-N5000_20201007

HANWA Hanwa Electronic Ind. Co., Ltd.

Features

Low parastic ESD Tester available

Simultaneous plural zapping is practicable
  Installing Max. 8 sockets and simultaneous plural zapping into each socket are possible.
Effective use of existing asset
  Socket board, which is equipped with conventional, ESD test instrument is usable. (HED-S5000, HED-F5000 series)
Adaptable to various standard waveforms
  This corresponds with domestic and abroad standard such as ESDA_JEDEC JS-001 (AEC), JEITA standards.
Adaptable to Latch-up test
  This corresponds with ESD pulse zapping method, V_{supply} over-voltage zapping method and constant current pulse zapping method.
Vector (Option)

# The configuration and function of system

The equipment provides you the choice of test pin number:256 pins, 512 pins, 768 pins and 1024 pins.
※ 2/6 signifies DC power supply for bias. 2 represents 2 power supply type, 6 represents 6 power supply.

| Model	Test pin	ESD Test	Latch-up test (Option)
HED-N5256-D2/6	256pin	<Support for standards> Conforms to ESDA_JEDEC JS-001 (AEC), JEITA <Test model> MM(200PF, 0Ω)×2 HBM(100PF,1500Ω)×2 are featured as standard.	<Support for standards> Conforms to ESDA_JEDEC JS-001 (AEC), JEITA <Test model> ESD Latch-up test (200PF, 0Ω) Constant current Latch-up test V_{supply} over-voltage test
HED-N5512-D2/6	512pin		
HED-N5768-D2/6	768pin		
HED-N51024-D2/6	1024pin		

Setting of ESD test and measurement result

Setting conditions of system that meets test device, setting conditions of test model and conditions of pulse zapping, etc. are performed easily and speedy. All of these can be saved on local disk.
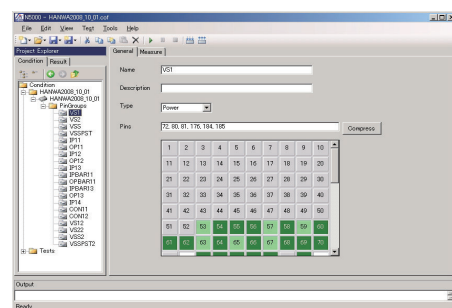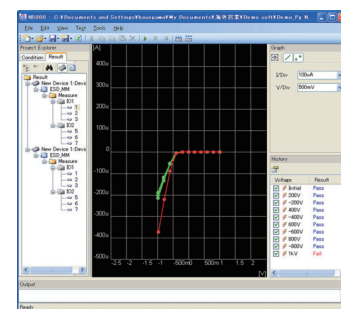

Pin group setting
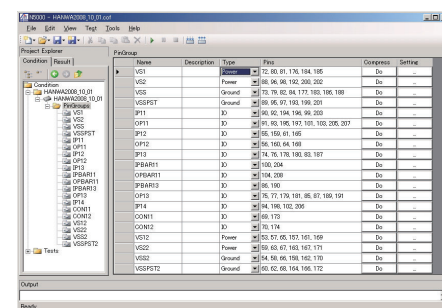
Measurement conditions of Leakage
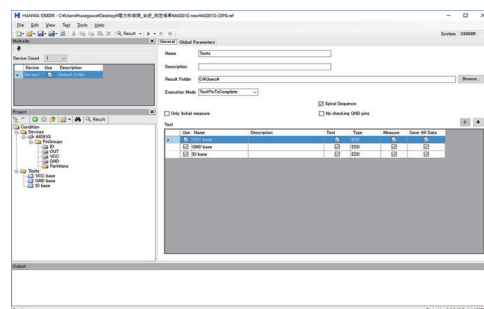
Test plan setting

ESD Result

Specification

Model	HED-N5000
Capacity of power supply	256 and 512 pins 100V/15A, 768 and 1024 pins 100V/20A
Pin number of max. measurement	256 pins, 512 pins, 768 pins and 1024 pins
Pulse zapping unit	MM×2 and HBM×2 are featured as standard
Pulse voltage	MM:10 ∼ +/-4000V, HBM:10 ∼ +/-8000V (Option)
Pulse voltage step	+/-5V
Pulse zapping number	1 ∼ 99 times
Pulse interval	0.1 ∼ 9.9s
Accuracy of charge voltage	1%+/-10V
Bias DC power supply	+/-35V/1A (Option available)
Vsupply over-voltage power (for Latch-up test)	100V(1V step)
Vf/Im measurement power supply	+/-40V (0.1V step) / 100mA (Option available)
Accuracy of Vf/Im measurement	1%+/-(1/500FS+/-10nA)
Pulse current supply	+/-1A（1mA step)
Max count power supply	8
Wave form sampling (for Latch-up test)	10MHz, Max.4000 points
Destruction judgement	Changing amount judgement / Absolute value judgement
Vector (Option)	
Outer dimensions	1600mm(W)×900mm(D)×1500mm(H)
Weight	150 Kg ∼ 200 Kg
Basic software(OS)	Windows